

CHAPTER 15 CMOS DIGITAL LOGIC CIRCUITS

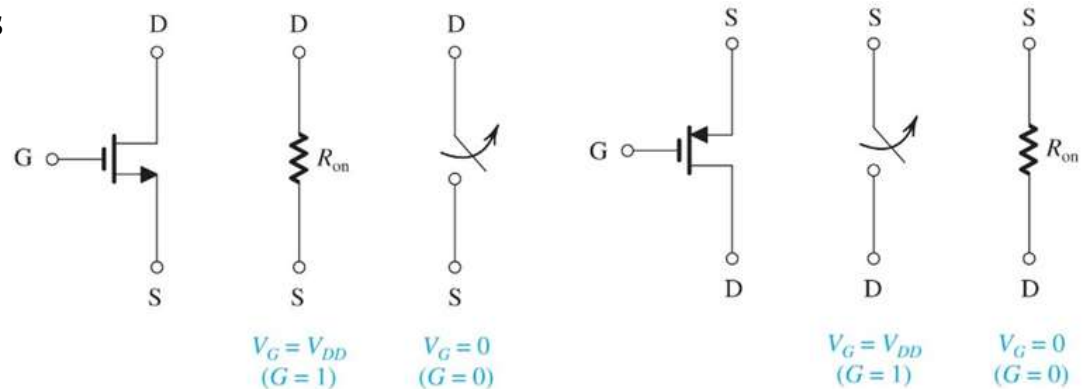
Chapter Outline

- 15.1 CMOS Logic-Gate Circuits
- 15.2 Digital Logic Inverters
- 15.3 The CMOS Inverter
- 15.4 Dynamic Operation of the CMOS Inverter
- 15.5 Transistor Sizing
- 15.6 Power Dissipation

15.1 CMOS Logic-Gate Circuits

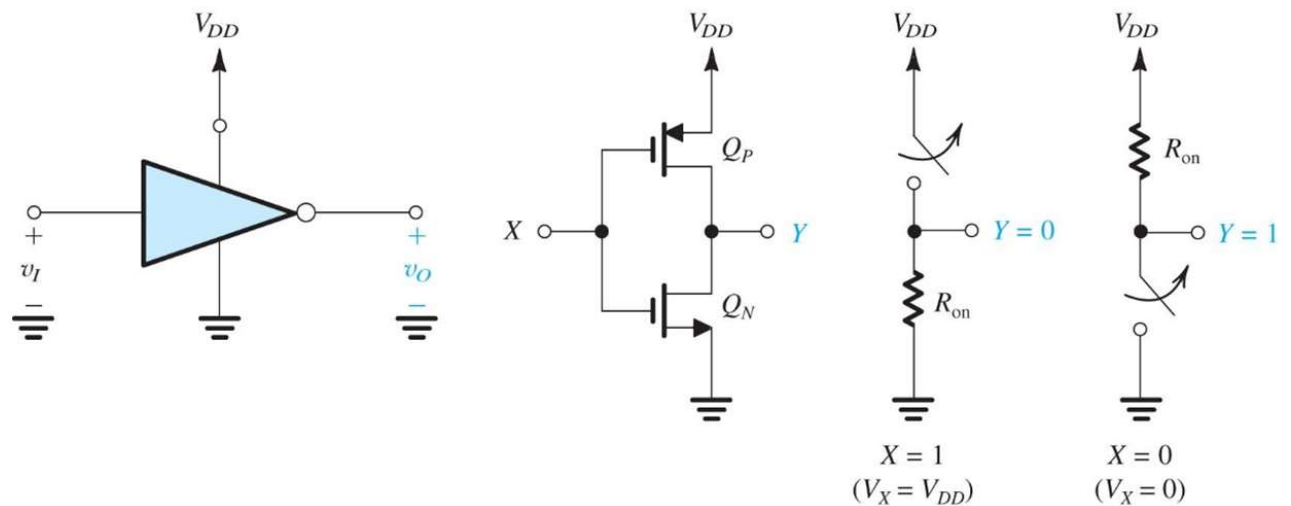
Switch-Level Transistor Model

- ❑ NMOS and PMOS transistors as switches
- ❑ Switch on: small resistance R_{on} or r_{DS}
- ❑ Switch off: open circuit



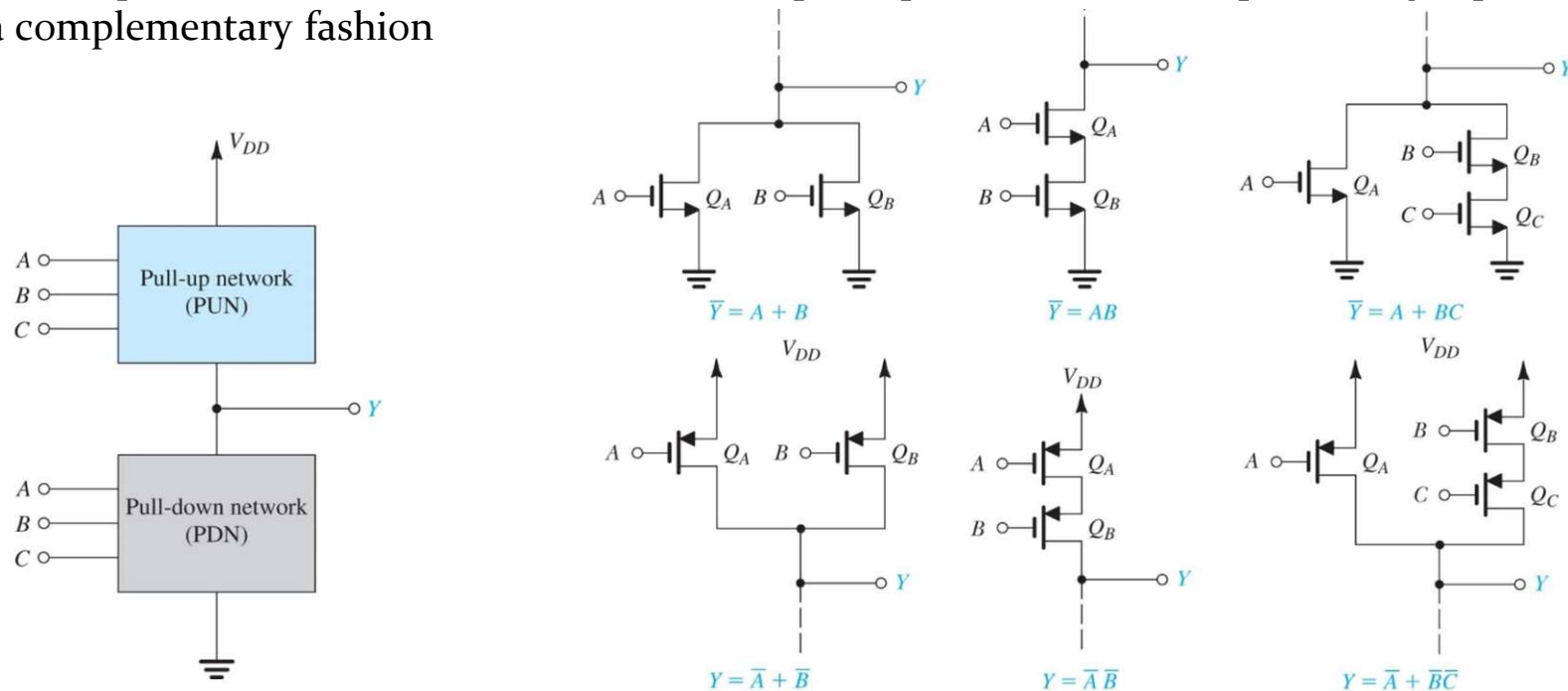
The CMOS Inverter

- ❑ Invert the logic value of the input
- ❑ Represented by Boolean expression $Y = \overline{X}$
- ❑ When $X = 1$ ($V_X = V_{DD}$)
 - $Y = 0$ ($V_Y = 0V$)
- ❑ When $X = 0$ ($V_X = 0V$)
 - $Y = 1$ ($V_Y = V_{DD}$)

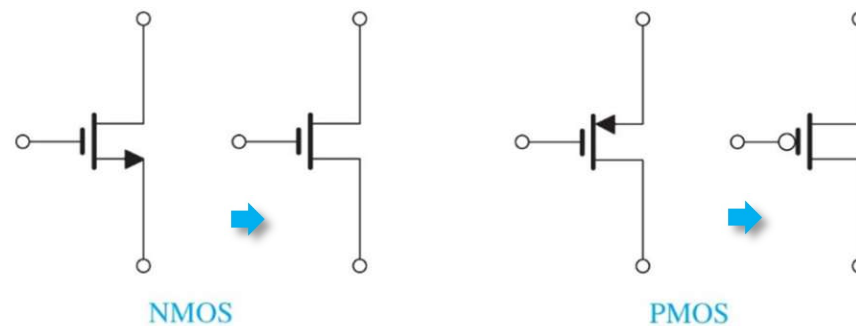


General Structure of CMOS Logic

- NMOS pull-down network (PDN) and PMOS pull-up network (PUN) operated by input variables in a complementary fashion



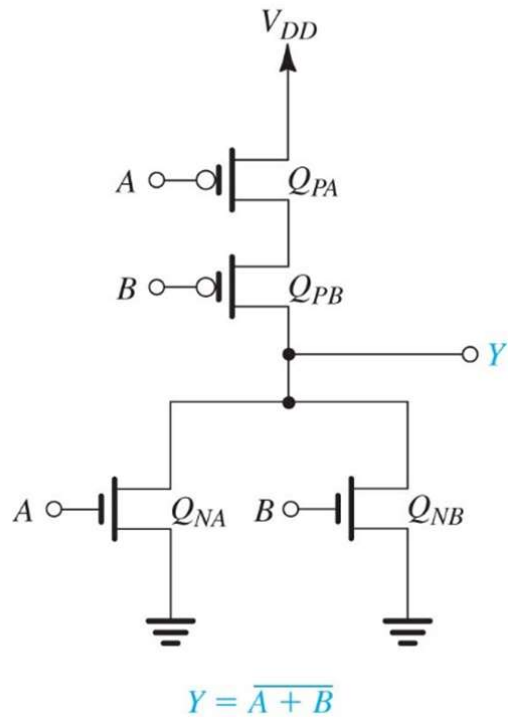
Alternative Circuit Symbols for MOSFETs in Digital Circuits



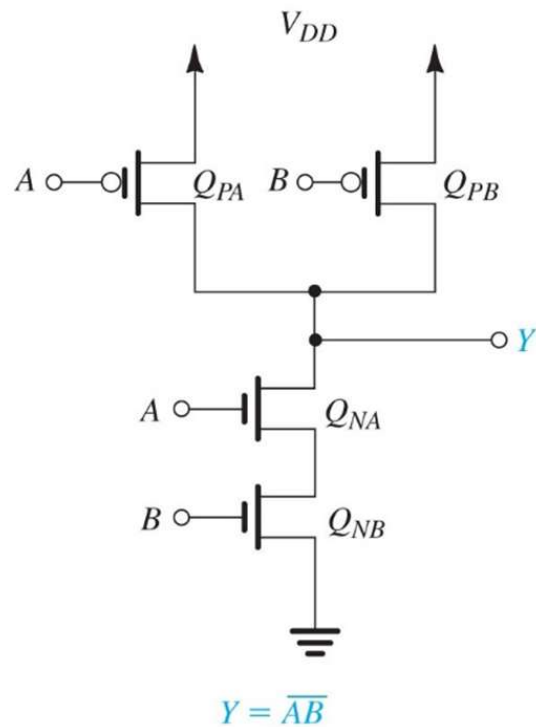
Two-Input Logic Gates

□ Two-input NOR gate, two-input NAND gate and Exclusive-OR gate

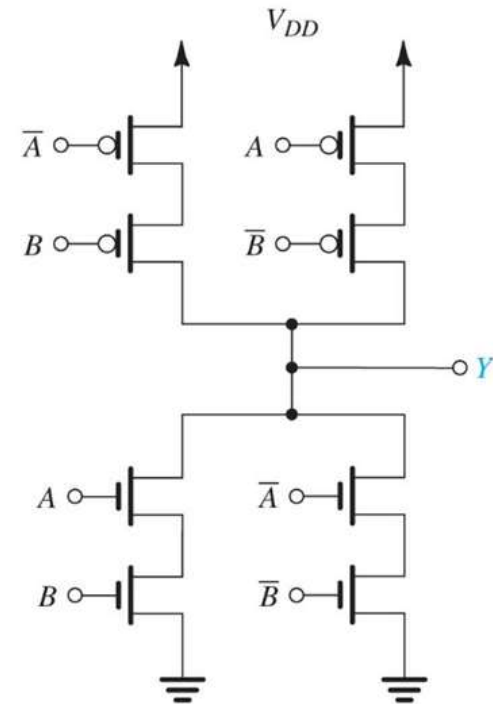
NOR gate



NAND gate

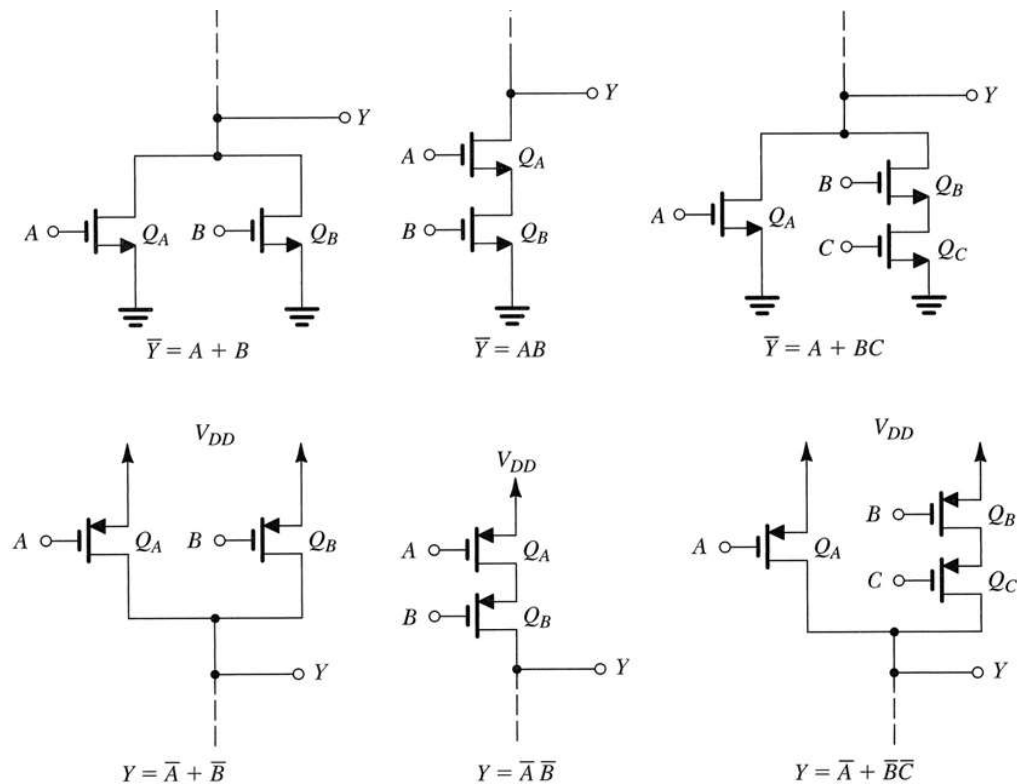


XOR gate

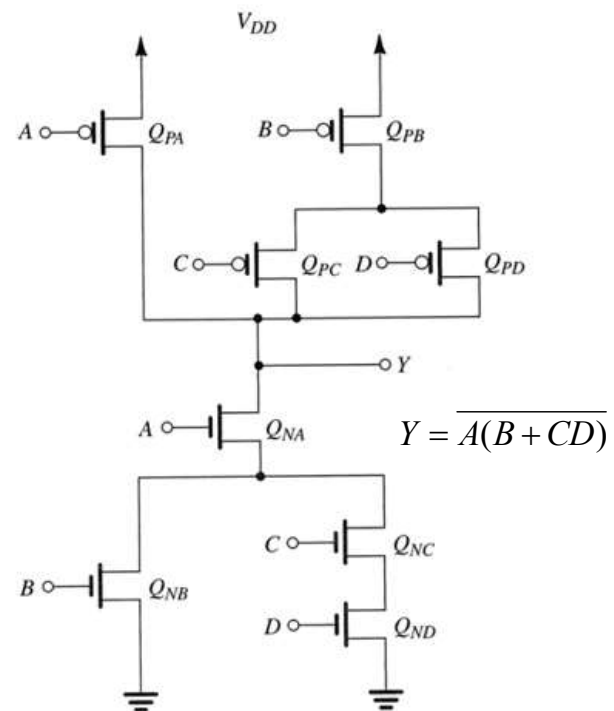
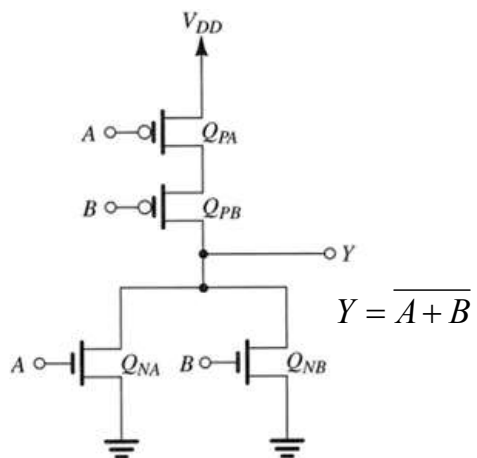
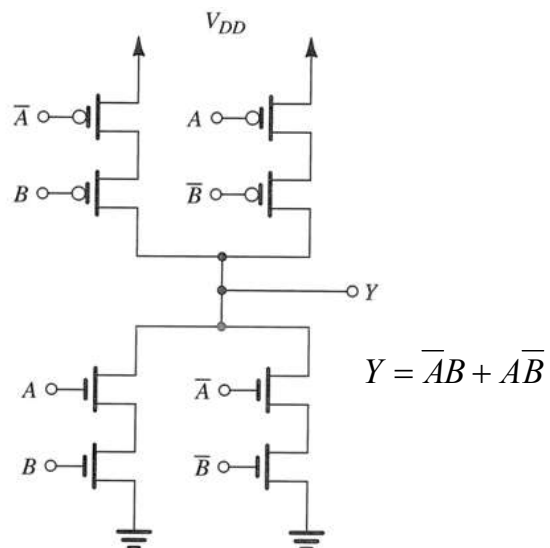
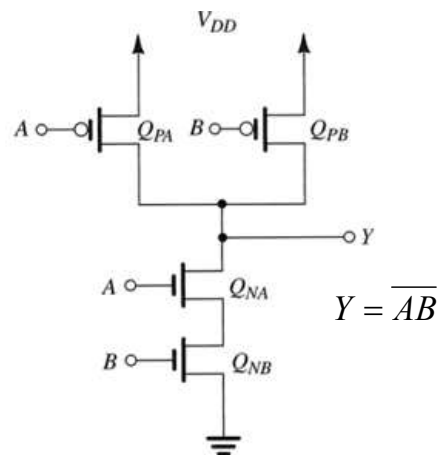


Synthesis Method for PUN and PDN

- ❑ The PDN can be directly synthesized by expressing the **inverted** Boolean function in **uncomplemented** variables (inverters are needed if complemented variables appear in the expression)
- ❑ The PUN can be directly synthesized by expressing the **nonverted** Boolean function in **complemented** variables (inverters are needed if uncomplemented variables appear in the expression)
- ❑ The PUN can be also obtained from the PDN (and vice versa) using the duality property



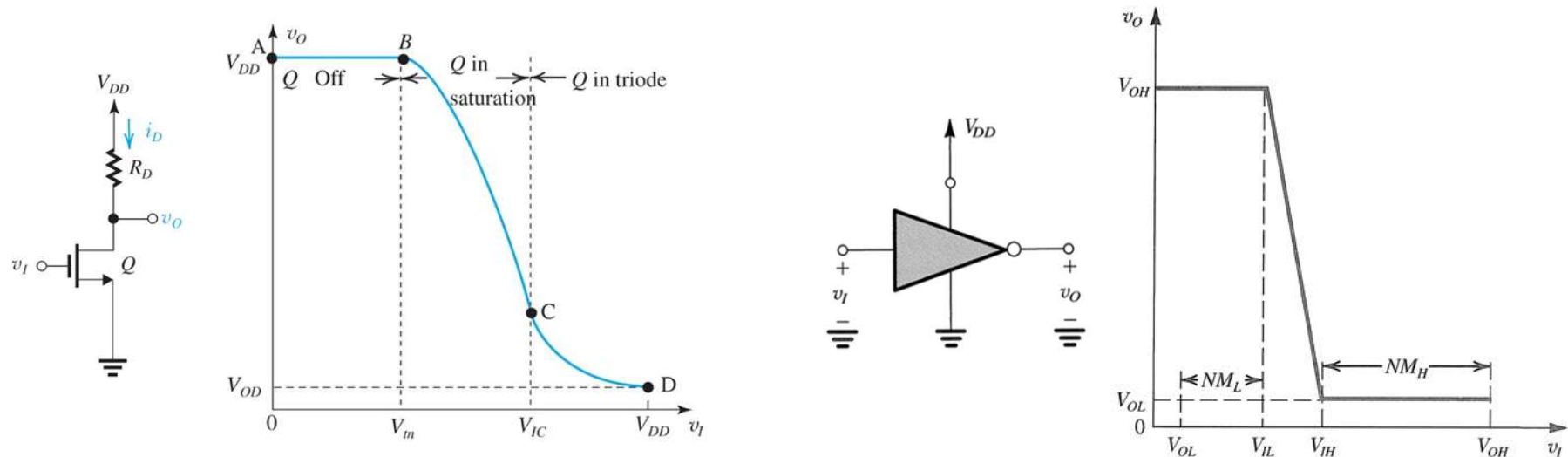
Examples for CMOS Logic Gates



15.2 Digital Logic Inverters

The Voltage-Transfer Characteristic (VTC)

- ❑ The function of the inverter is to invert the logic value of its input signal
- ❑ The voltage-transfer characteristic is used to evaluate the quality of inverter operation

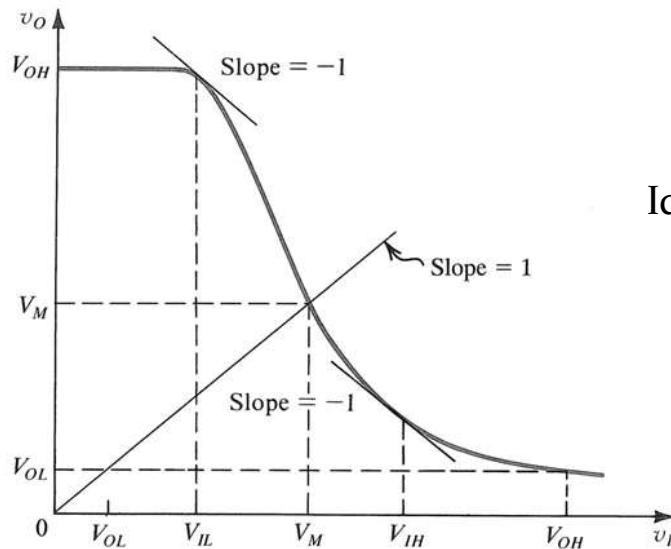
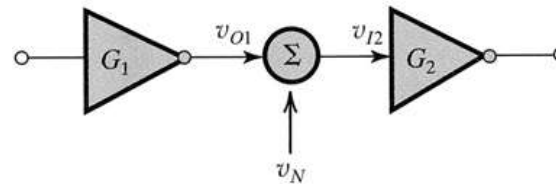


❑ VTC parameters

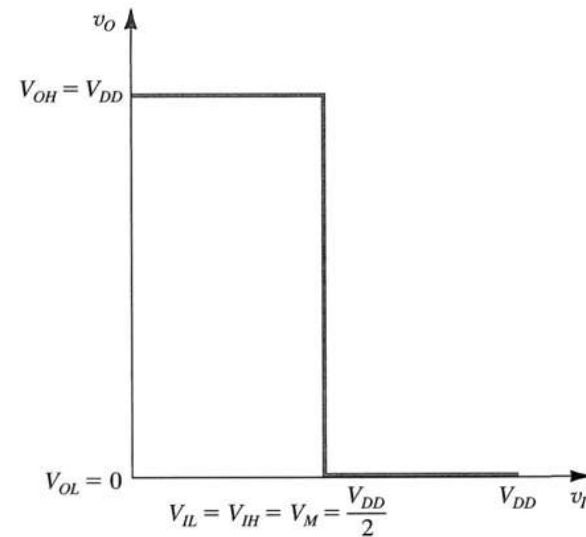
- V_{OH} : output high level
- V_{OL} : output low level
- V_{IH} : the minimum value of input interpreted by the inverter as a logic 1
- V_{IL} : the maximum value of input interpreted by the inverter as a logic 0
- Transition region: input level between V_{IL} and V_{IH}

Noise Margins

- ❑ The VTC is generally non-linear
- ❑ V_{IH} and V_{IL} are defined as the points at which the slope of the VTC is -1
- ❑ Robustness (noise margin at a high level): $NM_H = V_{OH} - V_{IH}$
- ❑ Robustness (noise margin at a low level): $NM_L = V_{IL} - V_{OL}$
- ❑ Static inverter characteristics for ideal VTC:
 - $V_{OH} = V_{DD}$
 - $V_{OL} = 0$
 - $V_{IH} = V_{IL} = V_{DD}/2$
 - $NM_H = NM_L = V_{DD}/2$

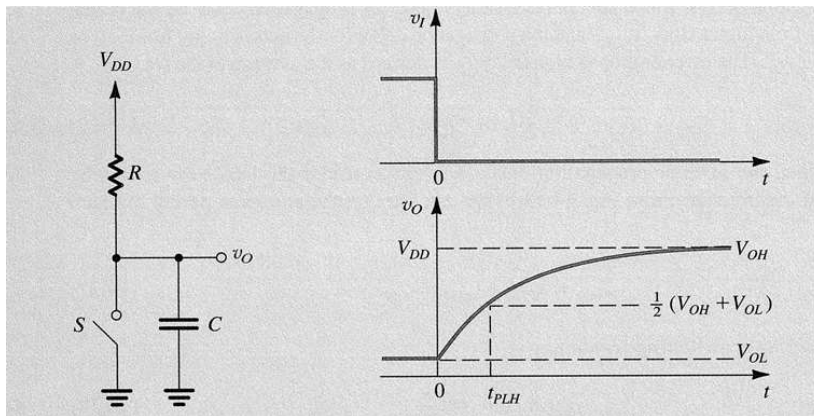


Ideal VTC

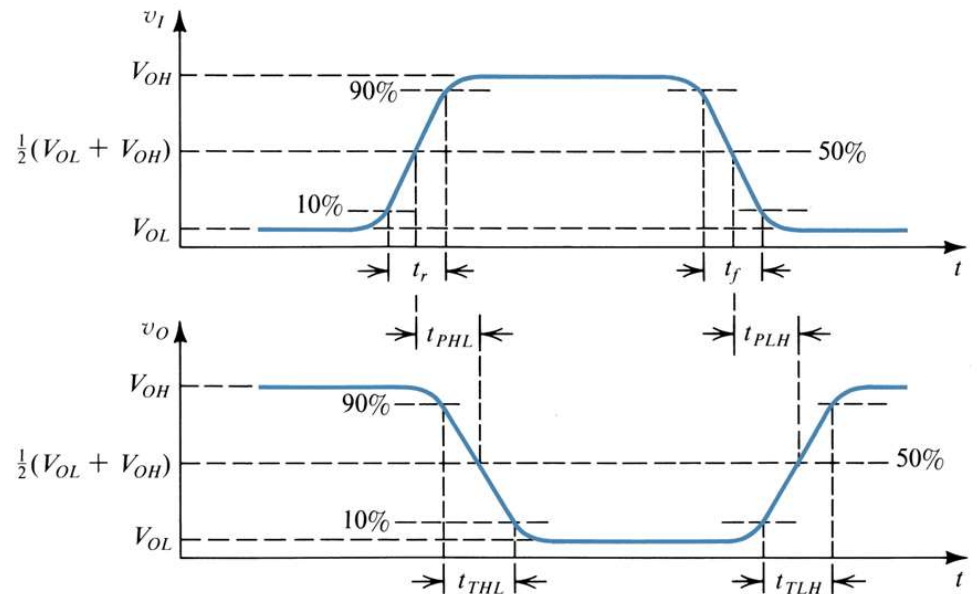


Propagation Delay

- ❑ t_{PHL} : high-to-low propagation delay
- ❑ t_{PLH} : low-to-high propagation delay
- ❑ t_p (propagation delay) = $(t_{PLH} + t_{PHL})/2$
- ❑ Maximum switching frequency $f_{\max} = 1/2t_p$
- ❑ The output transient of the inverter can be characterized by a RC charge/discharge model

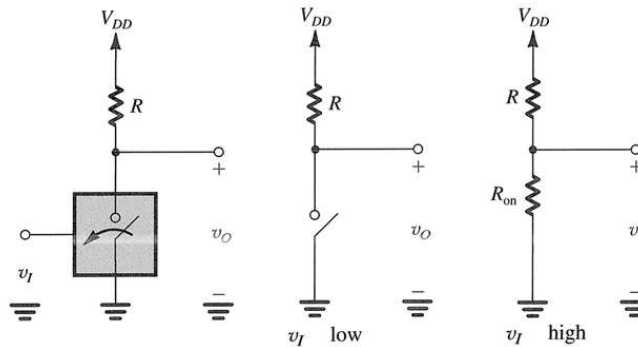


$$v_O(t) = V_{\infty} - (V_{\infty} - V_{0+})e^{-t/RC}$$

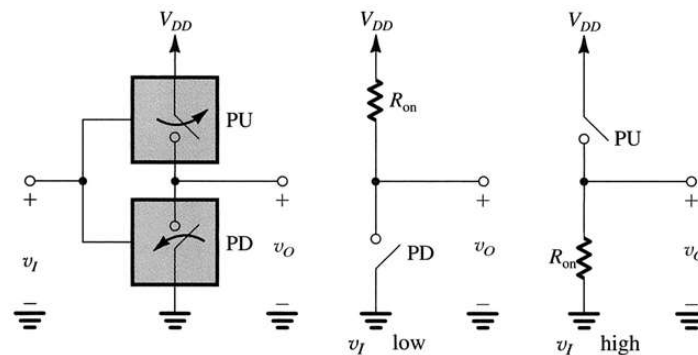


Inverter Implementation

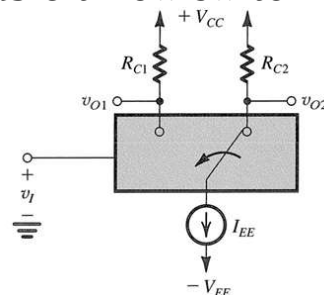
- Simplest implementation of the inverter with a MOSFET and a load



- Inverter implementation with complementary switches



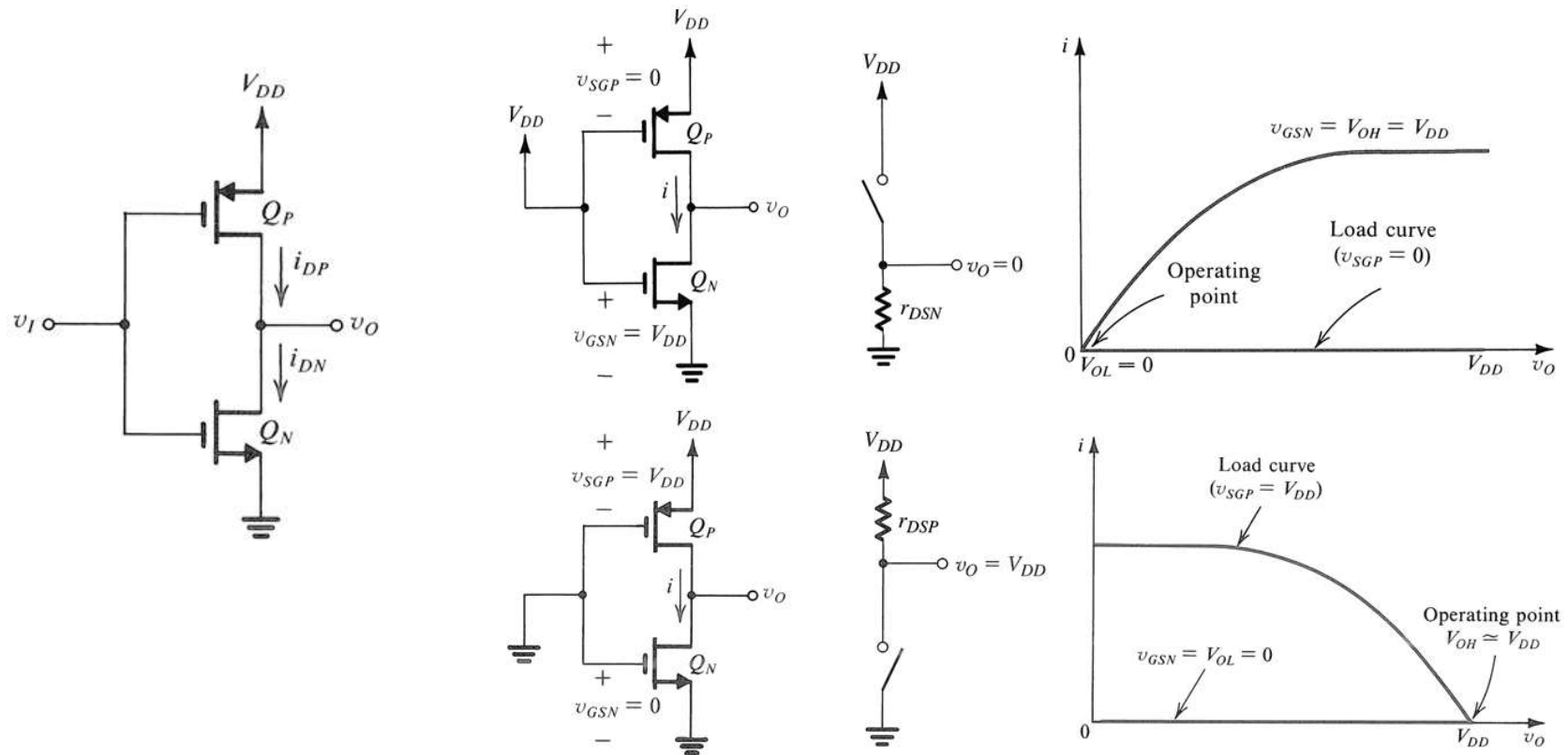
- Inverter implementation with a double-throw switch



15.3 The CMOS Inverter

Circuit Operation

- ❑ A CMOS inverter consists of an n-channel and a p-channel MOSFET
- ❑ The n-channel device turns on and the p-channel device turns off as the input level goes high
- ❑ The p-channel device turns on and the n-channel device turns off as the input level goes low
- ❑ The turn-on device is modeled by a resistance: $r_{DSN} = [k'_n(W/L)_n(V_{DD} - V_{tn})]^{-1}$ and $r_{DSP} = [k'_p(W/L)_p(V_{DD} - |V_{tp}|)]^{-1}$
- ❑ $V_{OH} = V_{DD}$ and $V_{OL} = 0$ for any CMOS inverter



□ The transistors go through five different operation regions as the input goes from 0 to V_{DD}

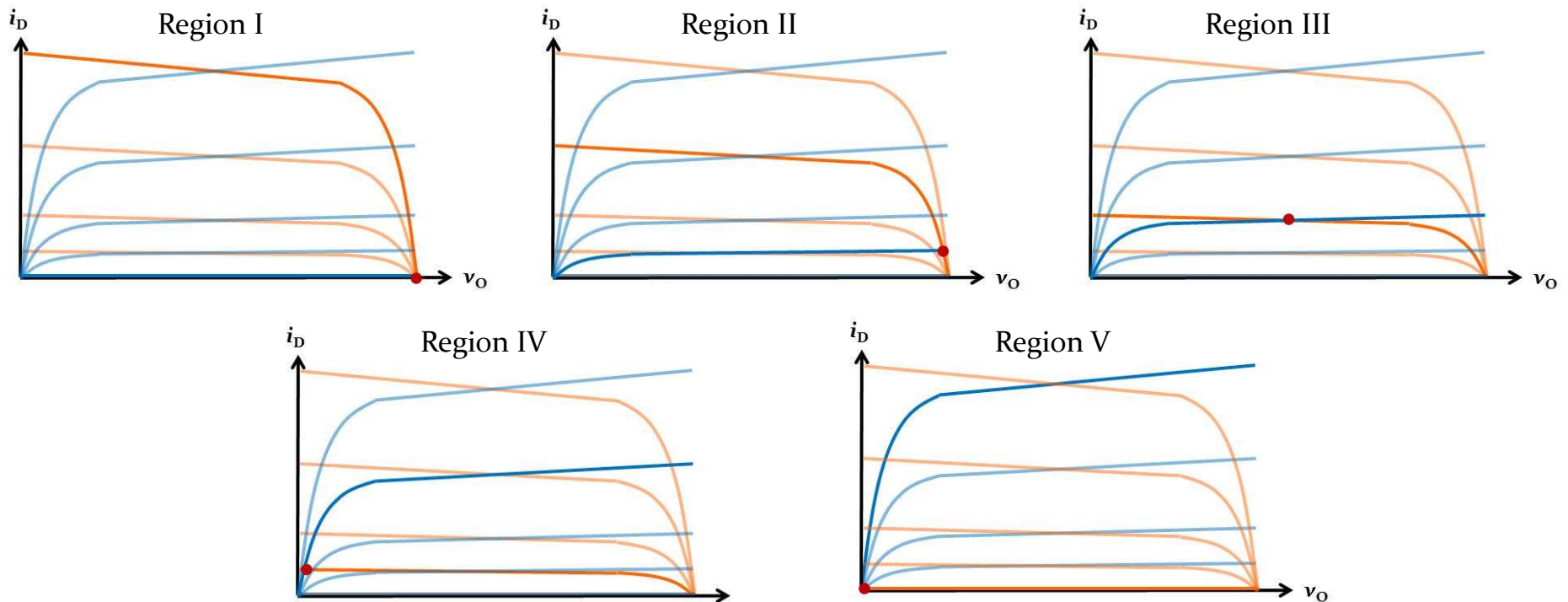
■ Region I: (Q_N off; Q_P tri.) $i_{DN}(=0) = i_{DP}$

■ Region II: (Q_N sat.; Q_P tri.) $i_{DN} = \frac{1}{2} k_n (v_I - V_{tn})^2 = i_{DP} = k_p \left[(V_{DD} - v_I - |V_{tp}|)(V_{DD} - v_O) - \frac{1}{2} (V_{DD} - v_O)^2 \right]$

■ Region III: (Q_N sat.; Q_P sat.) $i_{DN} = \frac{1}{2} k_n (v_I - V_{tn})^2 = i_{DP} = \frac{1}{2} k_p (V_{DD} - v_I - |V_{tp}|)^2$

■ Region IV: (Q_N tri.; Q_P sat.) $i_{DN} = k_n \left[(v_I - V_{tn})v_O - \frac{1}{2} v_O^2 \right] = i_{DP} = \frac{1}{2} k_p (V_{DD} - v_I - |V_{tp}|)^2$

■ Region V: (Q_N tri.; Q_P off) $i_{DN} = i_{DP}(=0)$



Static Characteristics of the CMOS Inverter

□ Ratioless logic: V_{OH} and V_{OL} are independent of ratio of the transistors

■ $V_{OH} = V_{DD}$

■ $V_{OL} = 0$

□ Static power dissipation is zero for both states

□ Noise margins can be determined by the VTC

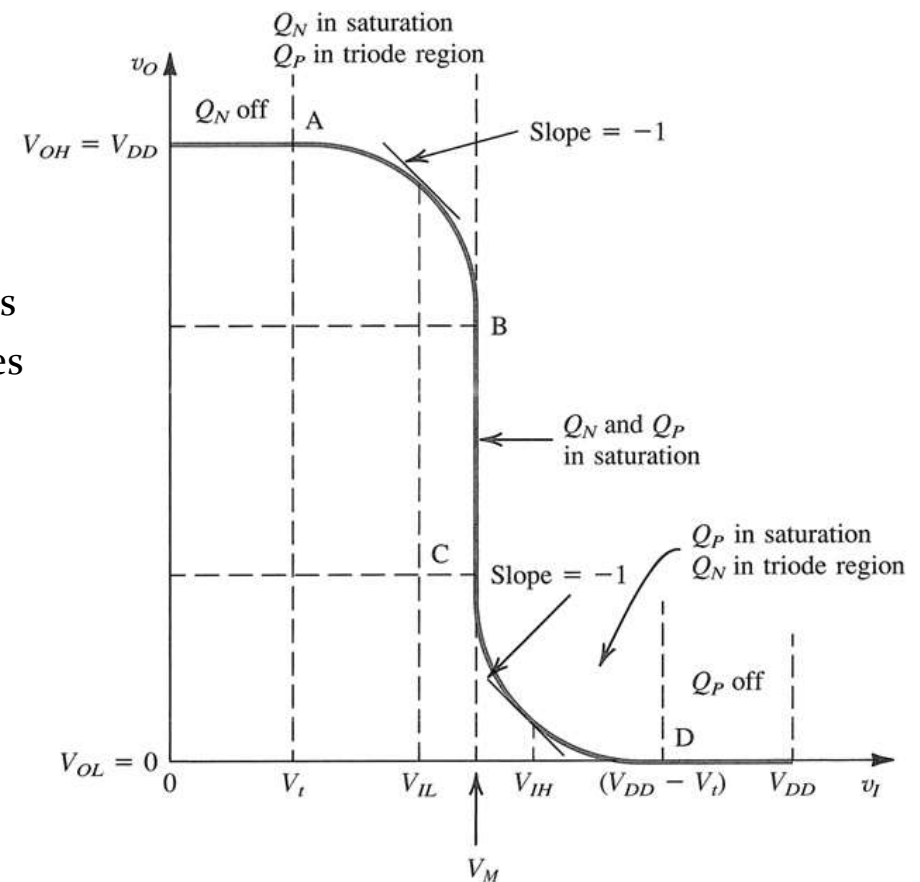
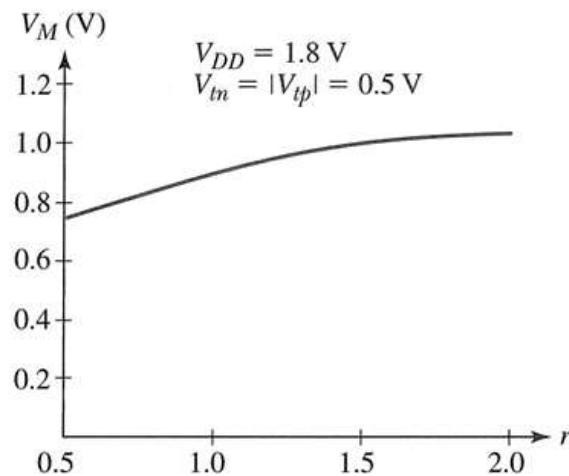
□ The switching voltage (when $v_I = v_O$) is defined by

$$V_M = \frac{r(V_{DD} - |V_{tp}|) + V_{tn}}{r+1} \quad \text{where} \quad r = \sqrt{\frac{k_p}{k_n}} = \sqrt{\frac{\mu_p(W/L)_p}{\mu_n(W/L)_n}}$$

■ V_M increases with r (not a strong function)

■ NM_L increases and NM_H decreases as r increases

■ NM_L decreases and NM_H increases as r decreases



The Matched Inverter

- ❑ A matched inverter has equivalent pull-up and pull-down device with $k_n = k_p$ and $V_{tn} = |V_{tp}| = V_t$
- ❑ The VTC is symmetric
- ❑ Determine V_{IL} from the VTC in Region II:

$$\frac{1}{2}(v_I - V_t)^2 = \left[(V_{DD} - v_I - V_t)(V_{DD} - v_O) - \frac{1}{2}(V_{DD} - v_O)^2 \right]$$

$$v_I - V_t = -(V_{DD} - v_O) - (V_{DD} - v_I - V_t) \frac{dv_O}{dv_I} + (V_{DD} - v_O) \frac{dv_O}{dv_I}$$

$$V_{IL} = \frac{1}{8}(3V_{DD} + 2V_t)$$

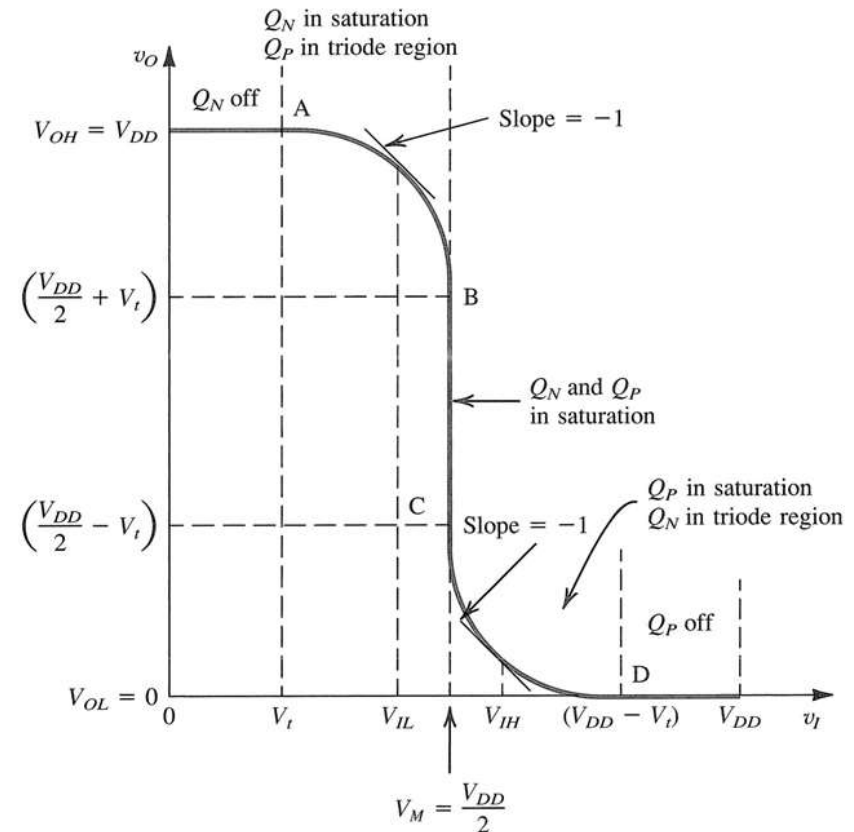
- ❑ Determine V_{IH} from the VTC in Region IV:

$$(v_I - V_t)v_O - \frac{1}{2}v_O^2 = \frac{1}{2}(V_{DD} - v_I - V_t)^2$$

$$v_O + (v_I - V_t) \frac{dv_O}{dv_I} - v_O \frac{dv_O}{dv_I} = -(V_{DD} - v_I - V_t)$$

$$V_{IH} = \frac{1}{8}(5V_{DD} - 2V_t)$$

- ❑ Noise margins: $NM_H = NM_L = (3V_{DD} + 2V_t)/8$
- ❑ Switching voltage: $V_M = V_{DD}/2$



15.4 Dynamic Operation of the CMOS Inverter

Determining the Propagation Delay

❑ Evaluated by charging/discharge the output capacitor C through Q_P and Q_N

❑ Average current method:

■ t_{PHL} :

$$I_{av} = \frac{1}{2} [i_{DN}(E) + i_{DN}(M)]$$

$$i_{DN}(E) = \frac{1}{2} k_n (V_{DD} - V_{tn})^2$$

$$i_{DN}(M) = k_n \left[(V_{DD} - V_{tn}) \left(\frac{V_{DD}}{2} \right) - \frac{1}{2} \left(\frac{V_{DD}}{2} \right)^2 \right]$$

$$t_{PHL} = \frac{CV_{DD}}{2I_{av}} = \frac{\alpha_n C}{k_n V_{DD}}$$

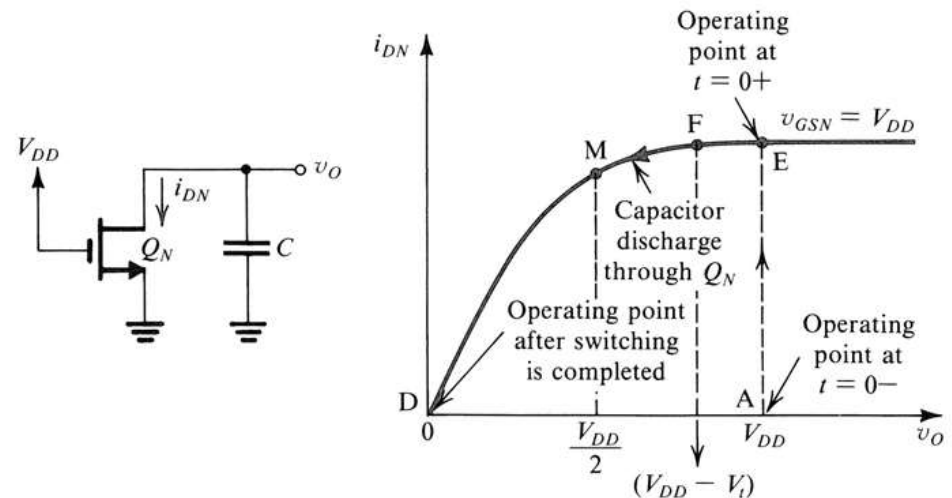
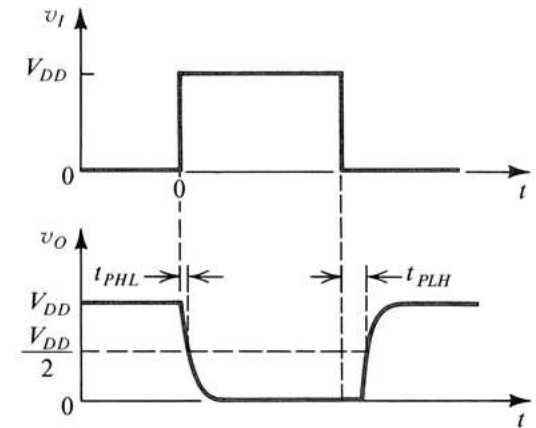
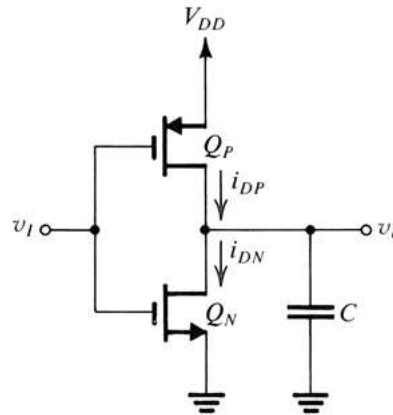
$$\text{where } \alpha_n = 2 / \left[\frac{7}{4} - \frac{3V_{tn}}{V_{DD}} + \frac{V_{tn}^2}{V_{DD}^2} \right]$$

■ t_{PLH} :

$$t_{PLH} = \frac{CV_{DD}}{2I_{av}} = \frac{\alpha_p C}{k_p V_{DD}}$$

$$\text{where } \alpha_p = 2 / \left[\frac{7}{4} - \frac{3|V_{tp}|}{V_{DD}} + \frac{V_{tp}^2}{V_{DD}^2} \right]$$

■ Propagation delay: $t_P = (t_{PHL} + t_{PLH})/2$



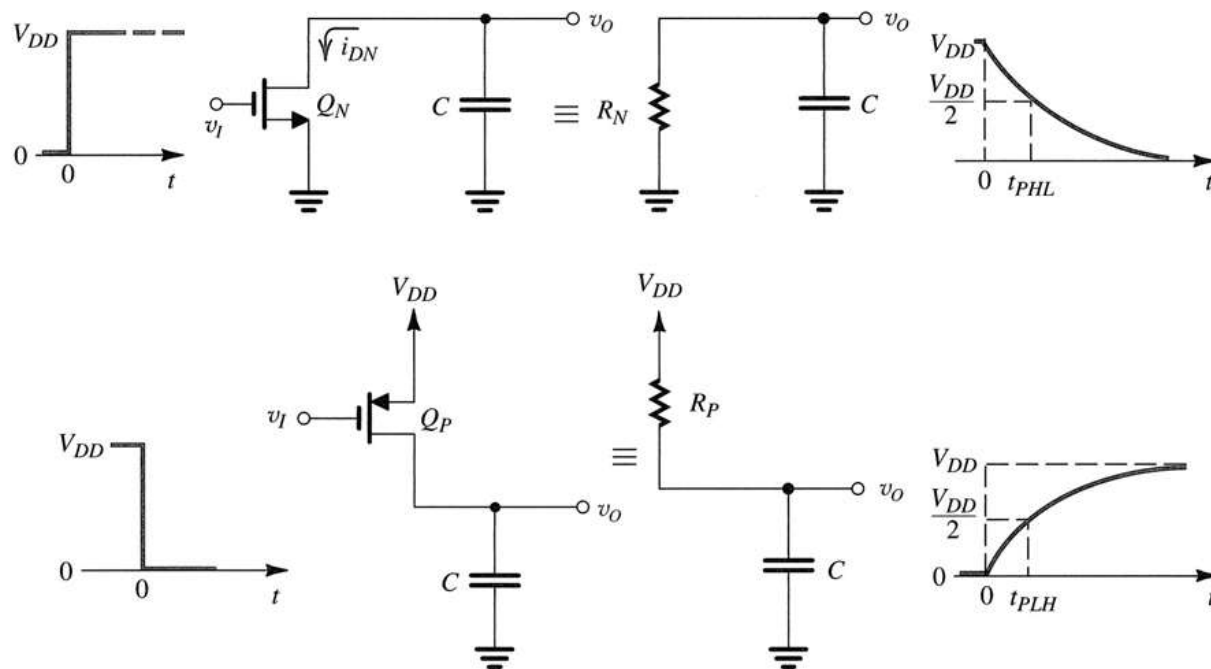
□ An alternative approach:

- Modeling the turn-on device as a resistance
- Use RC charge/discharge behavior to evaluate the propagation delay
- The empirical values of the resistors are given by

$$R_N = \frac{12.5}{(W/L)_n} (k\Omega) \quad \text{and} \quad R_p = \frac{30}{(W/L)_p} (k\Omega)$$

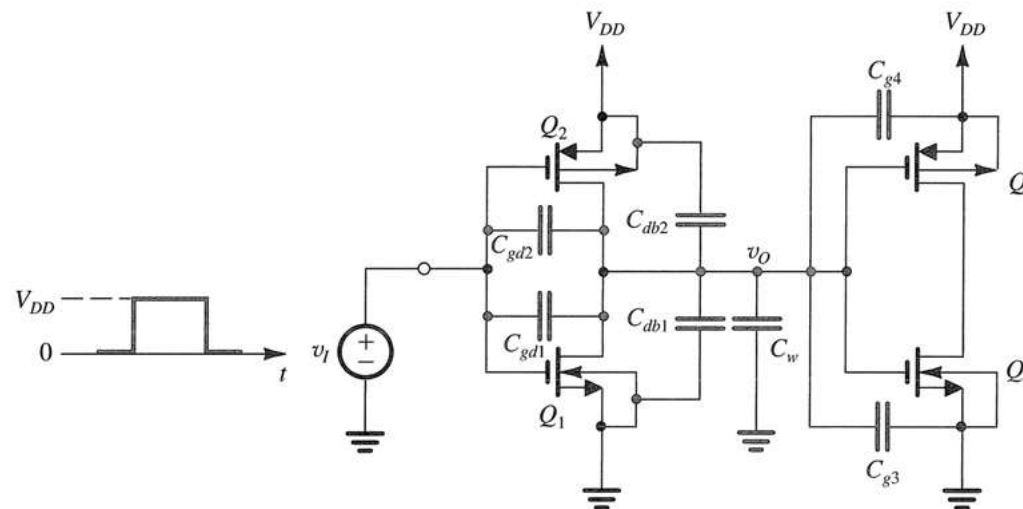
- $t_{PHL} = 0.69 R_N C$ and $t_{PLH} = 0.69 R_p C$

■ Step function at input may underestimate propagation delay $\rightarrow t_{PHL} \cong R_N C$ and $t_{PLH} \cong R_p C$

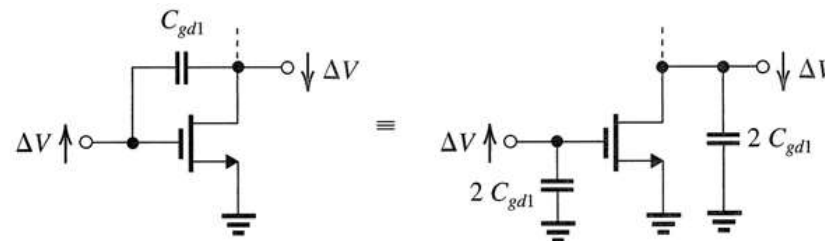


Determining the Equivalent Load Capacitance

- Components accountable for the equivalent load capacitance
 - Transistor parasitic capacitances from Q_1 and Q_2 (intrinsic component)
 - Input capacitance of the following stages (extrinsic component)
 - Wiring capacitance or interconnect capacitance (extrinsic component)



$$C = (2C_{gd1} + 2C_{gd2} + C_{db1} + C_{db2}) + (C_{g3} + C_{g4} + C_w) = C_{\text{int}} + C_{\text{ext}}$$



15.5 Transistor Sizing

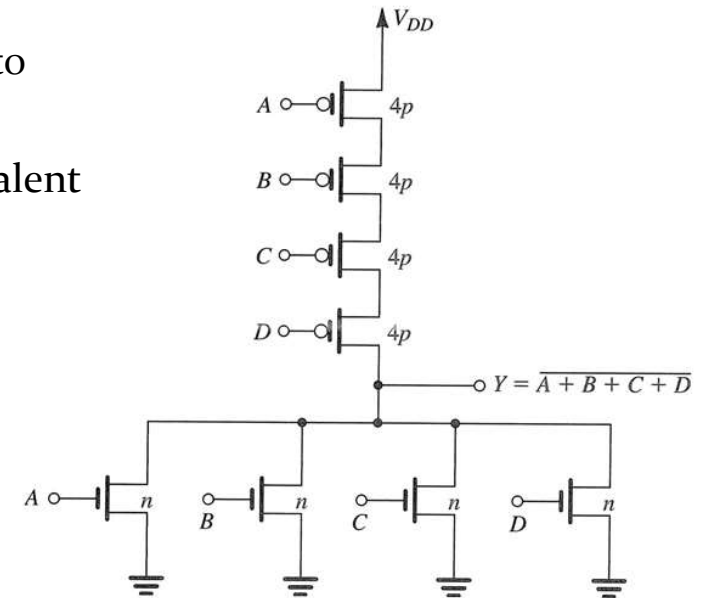
Inverter Sizing

- ❑ Minimum length permitted by the technology is usually used as the length for all channels
- ❑ Device aspect ratio $(W/L)_n$ is usually selected in the range 1 to 1.5
- ❑ The selection of $(W/L)_p$ is relative to $(W/L)_n$
 - Matched inverter by $(W/L)_p : (W/L)_n = \mu_n : \mu_p$
 - $(W/L)_p = (W/L)_n$: minimum area, small propagation delay
 - $(W/L)_p = 2(W/L)_n$: a frequently used compromise
- ❑ Transistor sizing (aspect ratios are increased by a factor of S) versus propagation delay
 - Load capacitance: $C = C_{\text{int}} + C_{\text{ext}} = SC_{\text{int}0} + C_{\text{ext}}$
 - Equivalent resistance: $R_{eq} = \frac{1}{2} \left(\frac{R_N}{S} + \frac{R_P}{S} \right) = \frac{R_{eq0}}{S}$
 - Propagation delay: $t_p = 0.69 \left(\frac{R_{eq0}}{S} \right) (SC_{\text{int}0} + C_{\text{ext}}) = 0.69 \left(R_{eq0} C_{\text{int}0} + \frac{1}{S} R_{eq0} C_{\text{ext}} \right)$
- ❑ The propagation decreases as S increases for cases where C_{ext} dominates
- ❑ The propagation is nearly independent of the transistor sizing (S) for cases where C_{int} dominates

Transistor Sizing

- ❑ The (W/L) ratios are chosen for a worst-case gate delay equal to that of the basic inverter (assuming C is constant)
- ❑ The derivation of equivalent (W/L) ratio is based on the equivalent resistance of the transistors

$$r_{DS} \propto (W/L)^{-1} \left\{ \begin{array}{l} \text{Series Connection} \rightarrow (W/L)_{eq} = \left[\frac{1}{(W/L)_1} + \frac{1}{(W/L)_2} + \dots \right]^{-1} \\ \text{Parallel Connection} \rightarrow (W/L)_{eq} = (W/L)_1 + (W/L)_2 + \dots \end{array} \right.$$

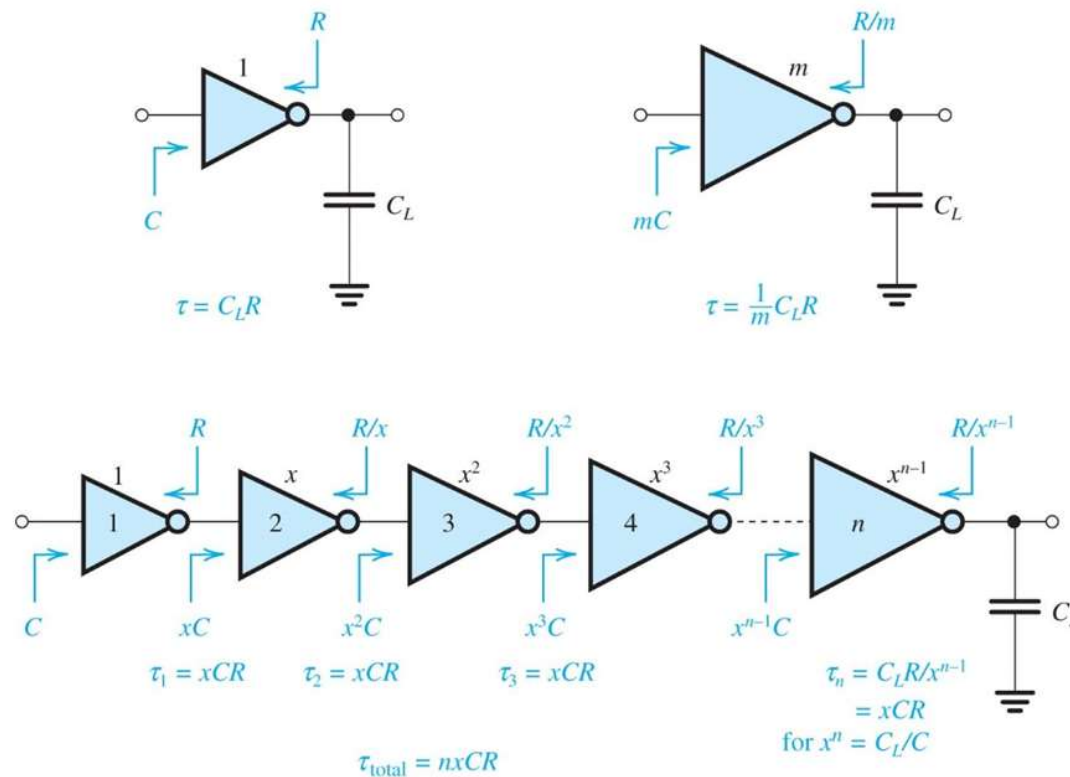


Effects of Fan-In and Fan-Out

- ❑ Each additional input to a CMOS gate requires two additional transistors
- ❑ Increases the chip area and the propagation delay due to excess capacitive loading
- ❑ The number of NAND gate is typically limited to 4
- ❑ Redesign the logic design may be required for a higher number of inputs
- ❑ Advantages of using CMOS logic: static power dissipation, ratioless design, noise margin
- ❑ Disadvantage of using CMOS logic: area, complexity, capacitive loading, propagation delay

Driving a Large Capacitance

- ❑ A large capacitive load drastically increases the propagation delay
- ❑ Use a large inverter to drive the load could alleviate the propagation delay
- ❑ The input capacitance increases accordingly equivalently shifting the burden forward
- ❑ Chain of scaled inverters in cascade to alleviate the problem with large capacitive load

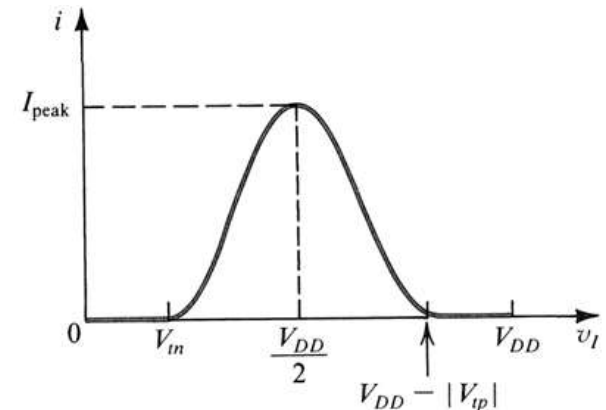
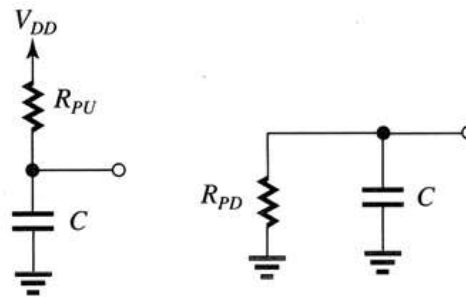


15. 6 Power Dissipation

Power Dissipation

- ❑ Static power dissipation: power dissipated when the inverter stays in logic 0 or logic 1
- ❑ Dynamic power dissipation: power dissipated as the output is switching
 - $0.5C(V_{DD})^2$ is dissipated in the PUN in each cycle
 - $0.5C(V_{DD})^2$ is dissipated in the PDN in each cycle
 - Dynamic power dissipation: $P_D = fC(V_{DD})^2$
- ❑ Another component of power dissipation during switching results from the current conduction through Q_P and Q_N and the peak current for a matched inverter is given by

$$I_{peak} = \frac{1}{2}k_n \left(\frac{V_{DD}}{2} - V_{tn} \right)^2$$



Power-Delay Product and Energy-Delay Product

- ❑ Power and delay are often in conflict for inverter operation
- ❑ Power-delay product is a figure-of-merit for comparing logic-circuit technologies or families
- ❑ Power-delay product is defined as $PDP = P_D t_p = CV_{DD}^2 / 2$
- ❑ Energy-delay product (energy per transition) is defined as $EDP = CV_{DD}^2 t_p / 2$